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Substitute for form 1449/PTO

Sheet 1

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necassary)

Complete if Known				
Application Number	Not Yet Received			
Filing Date	December 10, 2004			
First Named Inventor	Aviram Tam			
Art Unit	Not Yet Received			
Examiner Name				
Attorney Docket Number	40006317-0097-002			

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Examiner Initials*	Examiner Cite Document Number nitials* No.1 Number-Kind Code ^{2 (ff Ancient)}		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Occument	Pages, Columns, Lines, Where Relevent Passages or Relevant Figures Appear	
		^{US-} 6,480,807 B1	11/12/2004	Miyano Yumiko		
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		FORE	IGN PATENT DOCL	JMENTS		
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	L	EP 1 279 923 A	01/29/2003	Hitachi, Ltd.		
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant "Applicant's unique citation designation number (optional). "See Kinds Codes of USFTO Petent Documents at <a href="https://www.uspic.org/winder-policy-align-eq-align-

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PTO/SB/08B (07-05)

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Substitute for form 1449/PTO				Complete if Known			
Cubonia	10 10 10 11 14 10 17 10			Application Number			
INF	ORMATION	DIS	CLOSURE	Filing Date	December 10, 2004		
STATEMENT BY APPLICANT			PPLICANT	First Named Inventor	Aviram Tam		
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Sheet	2	of	2	Attorney Docket Number	40006317-0097-002		

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		APPLIED MATERIALS ISRAEL, LTD, International Search Report and Written Opinion, PCT/US2004/041884, 27 April 2005, pp	
		LEE TAE YONG ET AL.: "Experimental methodology of contact edge roughness on sub-100 nm pattern", Proceedings of SPIE: 24 May 2004, 10 pp	
		BUNDAY BENJAMIN D ET AL.: "CD-SEM Measurement of Line Edge Roughness Test Patterns for 193 nm Lithography", Proceedings of SPIE: July 2003, 15 pp	
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Signature	Considered	

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